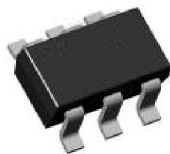


# SSF2145CH6

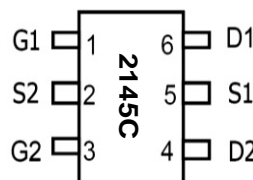
## 20V N-Channel and P-Channel Complementary MOSFET

### Main Product Characteristics

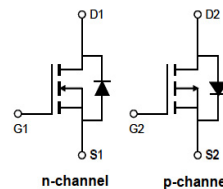
	N-Ch	P-Ch
$V_{DSS}$	20V	-20V
$R_{DSon}(typ.)$	38m $\Omega$	64m $\Omega$
$I_D$	4.8A	-2.9A



TSOP-6



Marking and Pin Assignment



Schematic Diagram

### Features and Benefits

- Advanced trench MOSFET process technology
- Designed for load switching and battery protection applications
- 150°C operating temperature



### Description

The SSF2145CH6 utilizes the latest trench processing techniques to achieve high cell density, low on-resistance and high repetitive avalanche rating. These features make this device extremely efficient and reliable for use in load switchings and a wide variety of other applications.

### Absolute Max Ratings

Symbol	Parameter	Max.		Units
		N-channel	P-channel	
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 4.5\text{V}^{(1)}$	4.8	-2.9	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 4.5\text{V}^{(1)}$	3.9	-2.4	
$I_{DM}$	Pulsed Drain Current <sup>(2)</sup>	17	-11	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation <sup>(3)</sup>	1.7	1.7	W
$V_{DS}$	Drain-Source Voltage	20	-20	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 8$	$\pm 8$	V
$T_J, T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	-55 to + 150	$^\circ\text{C}$

### Thermal Resistance

Symbol	Characteristics	Typ.	Max.		Units
			N-channel	P-channel	
$R_{\theta JA}$	Junction-to-Ambient ( $t \leq 10\text{s}$ ) <sup>(4)</sup>	—	76	114	$^\circ\text{C}/\text{W}$
	Junction-to-Ambient (PCB mounted, steady-state) <sup>(4)</sup>	—	53	53	$^\circ\text{C}/\text{W}$



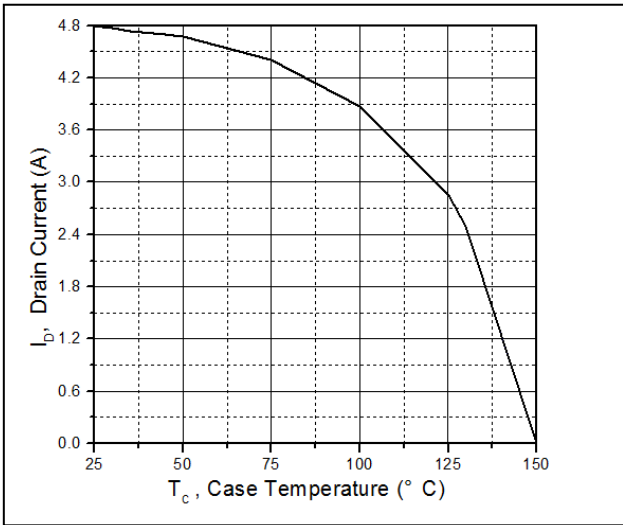
### Source-Drain Ratings and Characteristics

Symbol	Parameter		Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	N-Channel	—	—	4.8	A	MOSFET symbol showing the integral reverse p-n junction diode.
		P-Channel	—	—	-2.9		
$I_{SM}$	Pulsed Source Current (Body Diode)	N-Channel	—	—	17	A	
		P-Channel	—	—	-11		
$V_{SD}$	Diode Forward Voltage	N-Channel	—	0.69	1.2	V	$I_S=0.94A, V_{GS}=0V$
		P-Channel	—	-0.72	-1.2		$I_S=-0.75A, V_{GS}=0V$

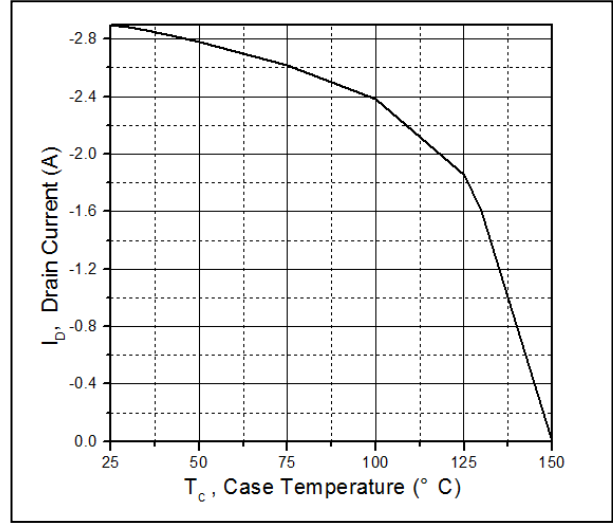
### Notes:

- ① The maximum current rating is limited by bond-wires.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-ambient thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ C$

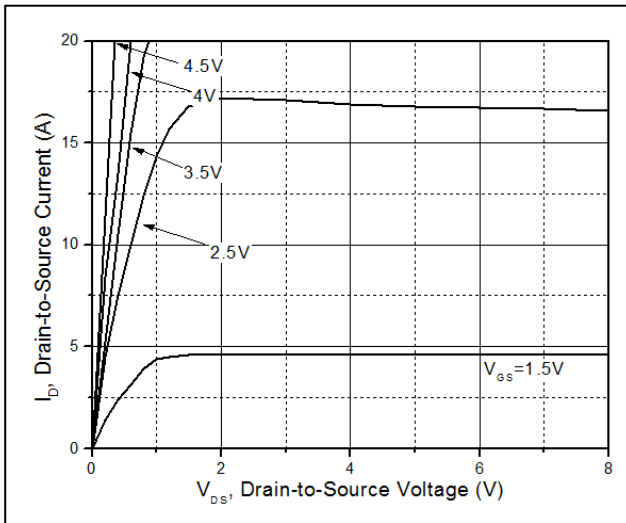
### Typical Electrical and Thermal Characteristics



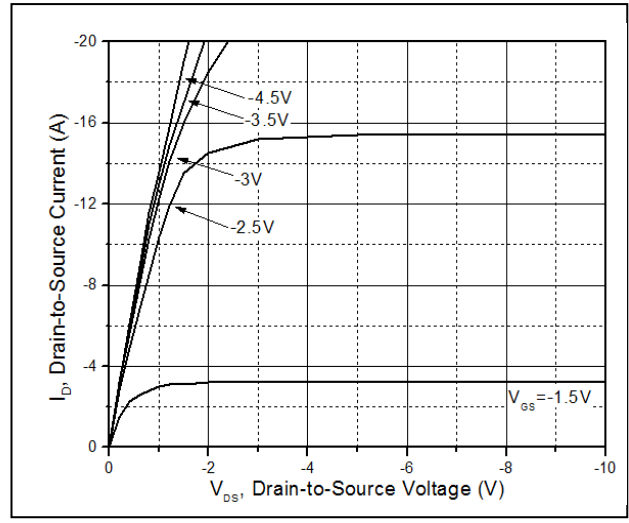
Maximum Drain Current Vs. Case Temperature(N-Channel)



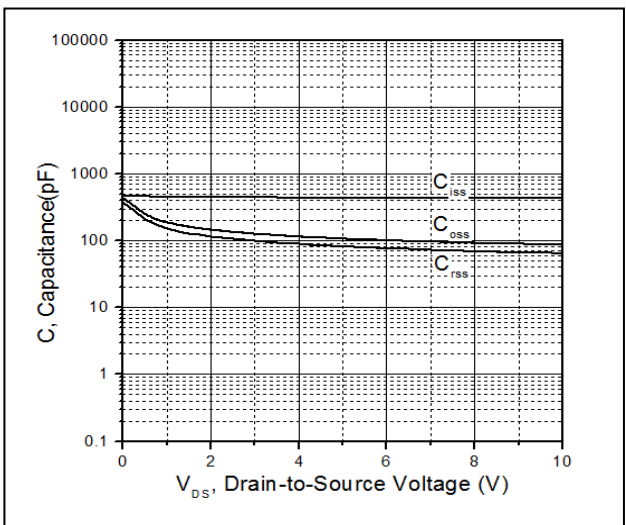
Maximum Drain Current Vs. Case Temperature(P-Channel)



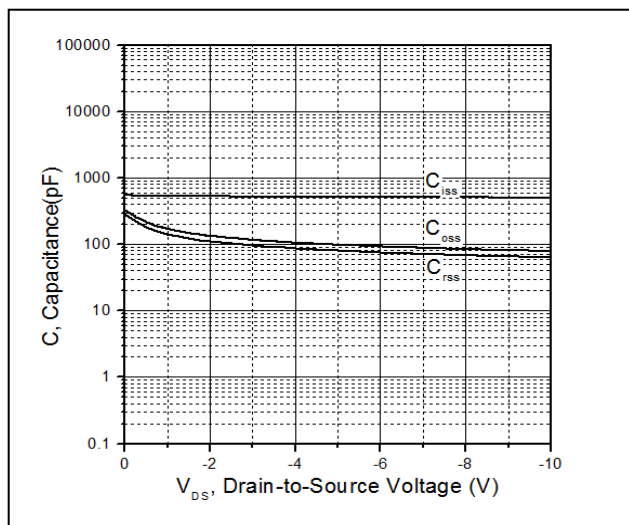
Typical Output Characteristics (N-Channel)



Typical Output Characteristics (P-Channel)

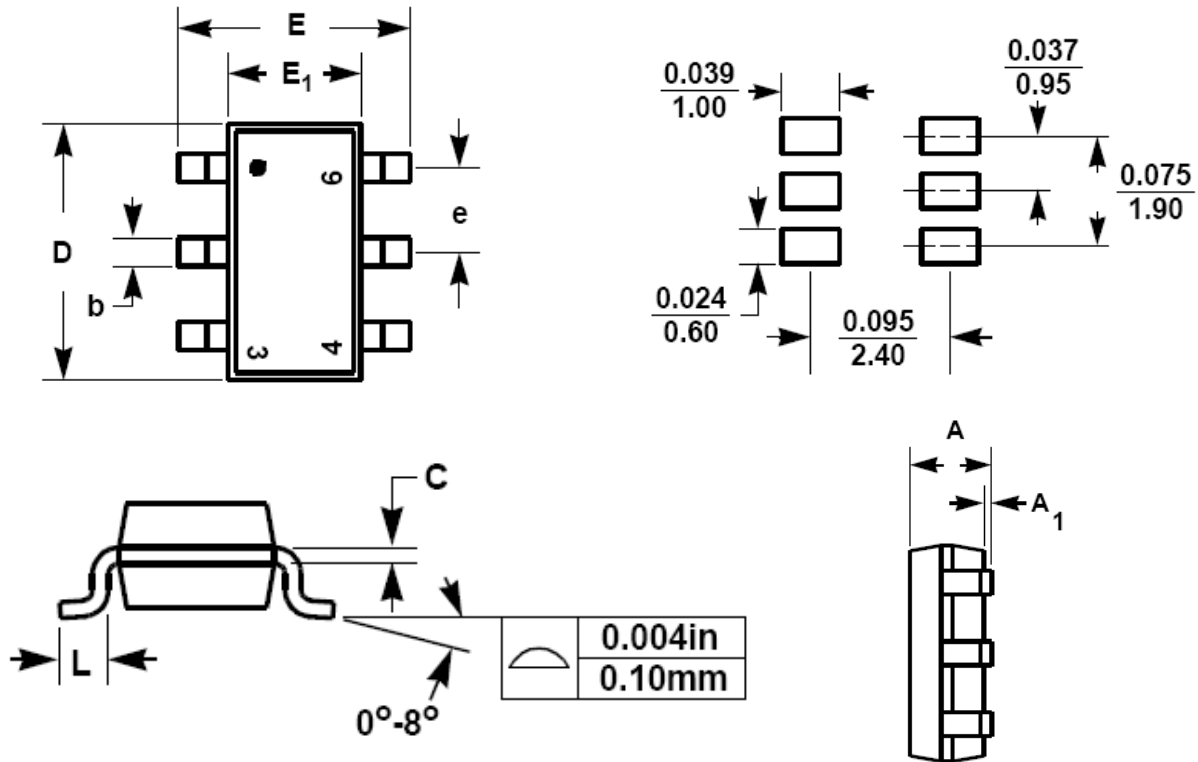


Typical Capacitance Vs. Drain-to-Source Voltage(N-Channel)



Typical Capacitance Vs. Drain-to-Source Voltage(P-Channel)

### Mechanical Data: TSOP-6



SYMBOL	Millimeters	
	MIN	MAX
A	0.90	1.10
A1	0.10	
b	0.30	0.50
c	0.08	0.20
D	2.70	3.10
E	2.60	3.00
E1	1.40	1.80
e	0.95 BSC	
L	0.35	0.55

### Notes:

- ① Dimensions are inclusive of plating
- ② Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 6 mils
- ③ Dimension L is measured in gauge plane.
- ④ Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.

## Ordering and Marking Information

<b>Device Marking: 2145C</b>  <b>Package (Available)</b> <b>TSOP-6</b>  <b>Operating Temperature Range</b> <b>C : -55 to 150 °C</b>
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## Devices per Unit

Package Type	Units/ Tube	Tubes/ Inner Box	Units/ Inner Box	Inner Boxes/ Carton Box	Units/ Carton Box
TSOP-6	3000pcs	10pcs	30000pcs	4pcs	120000pcs

## Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	$T_j=125^{\circ}\text{C}$ or $150^{\circ}\text{C}$ @ 80% of Max $V_{DSS}/V_{CES}/V_R$	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	$T_j=125^{\circ}\text{C}$ or $150^{\circ}\text{C}$ @ 100% of Max $V_{GSS}$	168 hours 500 hours 1000 hours	3 lots x 77 devices